An Instrument for the Measurement of the Resolving 507/18-37-1-7/21 Power and the Light Output of Fluorescing Screens (PR)

power of a screen up to a maximum of 500 lines sor us. The screen to be investigated is observed through an outlest microscope by a 20-40 fold magnification. The method devised by A. A. Lebedev is applied, by which a grating projected on the screen is investigated. The light outled is nonzered with a photocell and is given in candles per watt. I description follows of the mechanical construction of the instrument, of measuring devices and source of current. The authors thank their collaborators Yu. Y. Kushnir, V. I. Milyutin, and Ye. S. Rainer. There are 4 figures and

Card 2/2

507/48-23-6-6/28 Fetisov, D. V. Spektor, F. U., Milyutin, AUTHORS: V. I., Raspletin, K. K. On the Resolving Power of Electrostatic Electronic Miscroscopes TITLE: (O razreshayushchey sposobnosti elektrostaticheskogo elektronnogo mikroskopa) Izvestiya Akademii nauk SSSR. Seriya fizicheskaya, 1959, PERIODICAL: Vol 23. Nr 6. pp 690 - 693 (USSR) By the influence of aberration, caused by the asymmetry of ABSTRACT: the optical system, the chromatic aberration and other factors, the theoretically attainable resolving power of electrostatic electronic microscopes, which would be limited solely by electron diffraction and spherical aberration is not attained. In the present paper the influence exercised by the asymmetry of the field of electrostatic lenses and of the entire optical system, the influence of the variation of the spherical aberration of the lenses, and the effects of the pulsation of the acceleration voltage of the instrument are investigated. Field asymmetry depends on the geometric dimensions of the individual electrodes of the lenses, and, first of all, the connection between the oval electrodes of the lenses and resolving power is investigated. Card 1/2

On the Resolving Power of Electrostatic Electronic Microscopes

SOV/48-23-6-6/28

Results obtained by measurements show an increase in resolution with a reduction of the oval shape of the lens electrodes. In a similar manner the influence exercised by the aberration from the axial arrangement and the results obtained are shown by four diagrams (Figs 2,3). A stigmatizer is then briefly described, which is partly able to eliminate these errors. For the investigation of the spherical aberration of an electrostatic objective, in which the focal plane of the lens is outside the range of the field, a schematical drawing is first given, after which a constant of aberration is introduced. This constant depends on the geometric dimensions of the middle electrode and its potential. Various adjustments are investigated, and the results obtained are shown by a table. The most satisfactory results were obtained when the focal plane was approached as far as possible to the lens. Finally, the influence exercised by the pulsation of the direct current was investigated at various amplitudes exercised by them upon resolving power. There are 5 figures, 1 table, and 3 references, 1 of which is Soviet.

Card 2/2

22176

24,3300

S/048/61/025/004/025/048 B102/B212

94.3500 AUTHORS:

Pochtarev, B. I., Raspletin, K. K., and Fetisov, D. V.

TITLE:

A device for measuring the luminescence parameters of

fluorescent screens

PERIODICAL:

Izvestiya Akademii nauk SSSR. Seriya fizicheskaya, v. 25,

no. 4, 1961, 512-514

TEXT: This paper has been presented at the 9th Conference on Luminescence (Crystal Phosphors) which took place in Kiyev from June 20 to 25, 1960. It offers a brief description of the device NPC (PRS) developed by the authors for the investigation of the main characteristics of cathodoluminophores and fluorescent screens. The latest model of the PRS device is a universal electron-optical apparatus using a system of electrostatic lenses. The device makes it possible to investigate the resolution, the light yield, the composition of the luminescence spectrum, and the purity of the surface if exposed to an electron beam. The maximum resolution of the device is found at 700 lines/mm, the beam voltage can be varied from 0-30 kv and the beam current from 2·10⁻⁸-2·10⁻⁶ a. The excitation current may be in-Card 1/3

22176

A device for ...

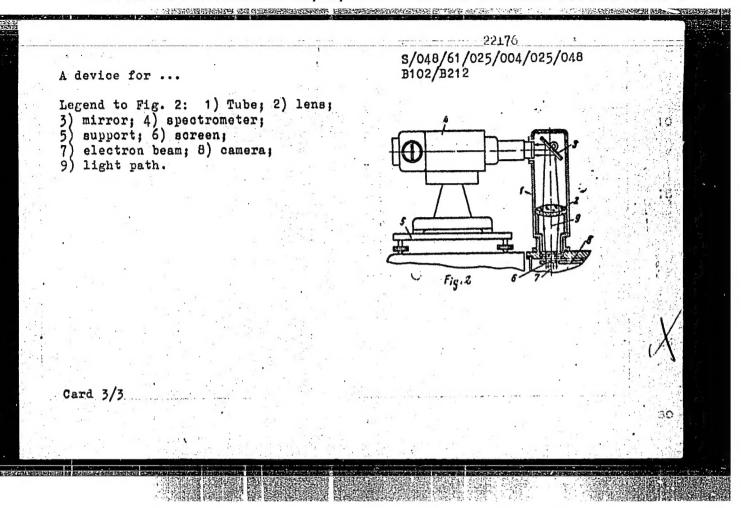
S/048/61/025/004/025/048 B102/B212

creased up to 1.10⁻⁵ a. The spot diameter on the screen (luminophore) is constant and measures 20 mm. The operating pressure in the chamber is (1-3)·10⁻⁴ mm Hg. 8-30 screens or 20 cuvettes with luminophore powder may be placed into the measuring chamber. The light yield of yellow-green or blue screens (luminophores) is measured with selenium and antimony-cesium photocells, respectively. The principle, design, and measuring operations of this device have been described earlier by the authors (Izv. AN SSSR, Ser. fiz. 23, No. 4, 462, 466 (1959)). Here, the measurement of the spectral composition of radiations is briefly described. This measurement is very easy to do in transmitted and also reflected radiation since the luminescence spectrum is nearly independent to obtain spectral curves, and a spectrograph or a monochromator is utilized. Fig. 2 shows the revolving optical system which is used to measure luminescence spectra. The authors thank Yu. M. Kushnir and M. A. Meyerov for advice, assistance, and interest. There are 2 figures and 1 Soviet-bloc reference.

Card 2/3

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"APPROVED FOR RELEASE: 08/23/2000 CIA-RDP86

CIA-RDP86-00513R000412920016-6

S/048/61/025/006/008/010 B117/B212

AUTHORS:

Kabanov, A.N. Kushnir, Yu.M., and Fetisov, D.V.

TITLE:

Objective recording method of energy spectra of electrons

for an electrostatic analyzer

PERIODICAL:

Akademiya nauk SSSR. Izvestiya. Seriya fizicheskaya, v. 25,

no. 6, 1961, 748-751

TEXT: The present paper has been presented at the 3rd All-Union Conference on Electron Microscopy, held in Leningrad from October 24 to 29, 1960. The authors have applied the method suggested by Möllenstedt (Ref.2: Möllenstedt G., Dietrich W., Optik, 12, 246 (1955)) for a 75-kv analyzer. For photographic recording of spectra the dispersing element of the analyzer consists of a slit and an analytical lens (Fig. 1 a). The principle of a device, where optical properties of the analytical lens and also the resolution and the intensity of the slit image remain constant, consists in introducing a second slit (Fig. 15 and B). It is located somewhat below the analytical lens, and is so far away from the optical axis that only those electrons will pass it, whose energies correspond to

Card 1/5

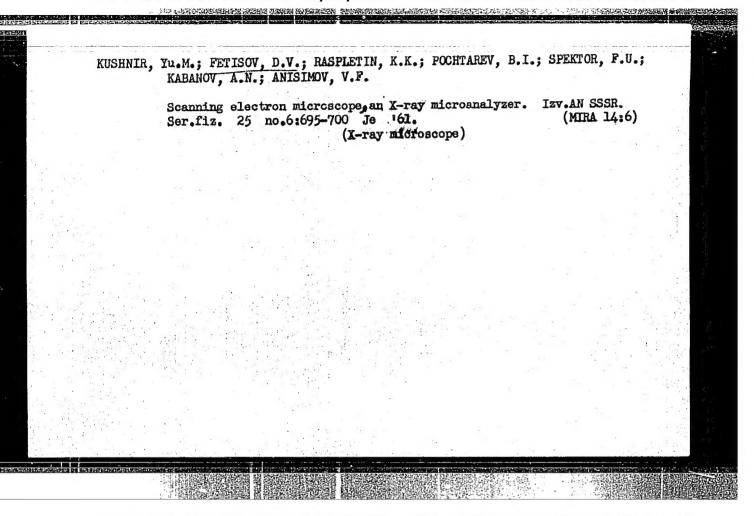
S/048/61/025/006/008/010 B117/B212

Objective recording method ...

the optimum conditions (Ront). Changing the potential of the central electrode of the analytical lens will keep the quantity R constant image of the slit canonly change its intensity. At the screen it remains unchanged. By adjusting optimum conditions for elastically scattered electrons and by continuous change of the central electrode potential, the number of electrons passing through the second slit is changed and it is possible to obtain easily information on the energy losses of the electrons and on the intensity of the spectral lines. The device can be simplified when using a semi-transparent fluorescent screen, a photo-electron multiplier and an automatic electronic potentiometer of the type 3Nn-0.9 (EPP-0.9). Fig. 2 shows a diagram of the dispersing element of the analyzer, the electron gun, and also the device for objective recording of electron energy spectra. Both slits are adjustable. The lower slit may be opened to a width that is sufficient to let the whole spectrum through. Control pictures of the spectrum may be taken with the camera without disturbing the vacuum. A movable photographic plate holder makes it possible to use both recording methods. After the electron beam has passed through the second slit, it hits the semi-transparent fluorescent screen with a short afterglow. The color of the afterglow and the spectral maximum correspond Card 2/5

-5 \$/048/61/025/006/008/010 B117/B212 Objective recording methods .. to the sensitivity of the photocathode of the \$\frac{4}{3}\gamma\$ (FEU) multiplier, of type 1 (1S). Organic glass was used as light conductor. The signal of the FEU multiplier is amplified by a d-c amplifier Y (U) and is fed to the input cf the balancing cathode follower KN (KP). This is used to coordinate the amplifier resistor and that of the potentiometer EPP-0.9. The change of the central electrode potential of the analytical lens was done with a NJ (PL) potentiometer. The total resistance of the potentiometer was 20 kilchms and its linearity 0.1%. The potentiometer was fed from a battery 6, (B,) of type 6AC (BAS) having a voltage of 150 v. The high-voltage divider Ro. made it possible to obtain the wanted conditions for the analytical lens, according to the current used for the electron beam. The battery (B.); 20 which was connected to the electron gun circuit, was used for recording standards for the energy spectra. A change of the resistance R, made it possible to adjust the current of the electron beam as necessary. The resolution of the analyzer was $\sim 140,000$: 1 and the dispersion 0.2 mm ev-1. Another article will report on the application of the analyzer with a device for objective estimation of the lines of energy spectra. There are 3 figures and 5 references: 3 Soviet-bloc and 2 non-Soviet-bloc. Card 3/5

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21399 \$/032/61/027/012/012/015 B104/B102

AUTHORS:

Kushnir, Yu. M., Fetisov, D. V., Rozenfel'd, L. B., and

Rozenfel'd, A. M.

TITLE:

Domestic electron microscopes for direct examination of

compact objects

PERIODICAL: Zavodskaya laboratoriya, v. 27, no. 12, 1961, 1528 - 1535

TEXT: The first part of this review paper deals with field-emission microscopes. A microscope of A. M. Rozenfel'd and P. V. Zaytsev (Izvestiya AN SSSR, ser. fizich. (in print)) and designed for testing thermionic and secondary-electron emitters is described. It differs from

the 99/1-75 (EEM-75) microscope in its vacuum system (10⁻⁶ mm Hg) and magnetic objective lens (Fig. 1). 40 kv can be applied between the cathode and anode (distance 2.5 mm) of the objective lens. The resolution can thus be increased to 350 - 400 Å. The objective lens permits the use of both electron and ion sources (Fig. 3). Air, hydrogen, helium, argon, and other ions can be used for exciting secondary electron emission. Card 1/5

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Domestic electron microscopes for ...

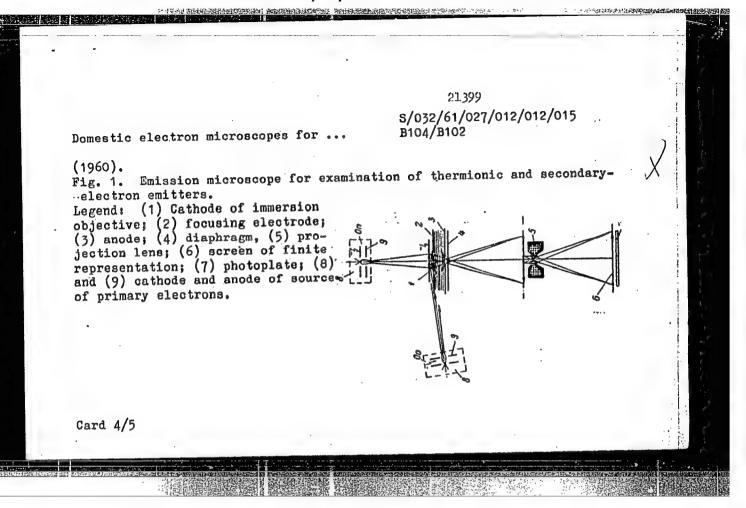
In this case, the resolution is approximately 2000 %. For the 33M-50 (EEM-50) microscope, an electrostatic immersion objective is being developed, which is designed to stretch and heat the specimen during examination. It can also be used for taking motion pictures of rapid processes. A field-emission microscope with electrostatic optics, developed by B. I. Popov and A. V. Druzhinin (2-e Soveshchaniye po elektronnoy mikroskopii, Nauchno-tekhnicheskoye obshchestvo im. A. S. Popov (annotatsii dokladov), M. (1958); Radiotekhnika i elektronika, no. 8 (1958)), is mentioned. The second part of this paper deals with reflecting electron microscopes which are known to operate like optical reflecting microscopes and have no high resolution owing to the large scattering of electron energies after reflection. At present, neither Russia nor other countries have such industrial electron microscopes. Some Japanese, British, and Russian transmission electron microscopes have attachments for observations in reflected light (Y3M-1,00 (UEM-100); Y3ME-100 (UEMB-100); NOMB-100 (UEMV-100)). The third part deals with scanning microscopes whose resolution reaches 500 - 200 A when operating with secondary electrons. When operating with X-rays, the resolvable distance is Card 2/5

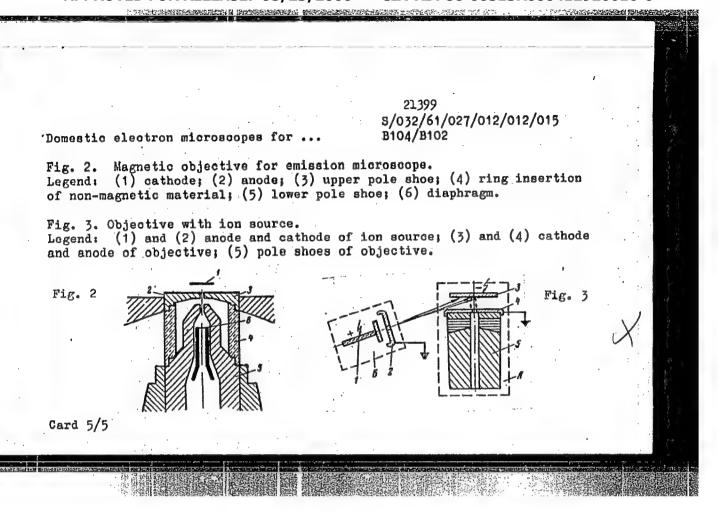
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Domestic electron microscopes for ...

approximately 1 ... A resolution of approximately 800 A was obtained for some objects examined under Soviet scanning microscopes with X-ray analyzers. These microscopes play an important role in the investigation of p-n junctions. The direct X-ray image was studied in previous experiments. In this case, the electrode probe scans a certain part of the specimen surface (0.3.0.3 mm). 50 pictures per sec can be developed with 35 /2 (35LKB2B) kinescope. Microchemical analyses with scanning microscopes are also described. The fourth part of the paper deals with reflection electron microscopes, in which accelerated electrons are slowed down and reflected in the microfield of the specimen. The image is determined by this microfield. The theoretical resolution of these microscopes is approximately 1000 A. Domestic microscopes differ from foreign types in that the images are produced in the vacuum part, whereby the quality of microphotographs is essentially improved. Magnification is about 2000. There are 10 figures and 25 references: 16 Soviet and 9 non-Soviet. The three most recent references to English-language publications read as follows: D. A. Melford a. P. Duncumb. Metallurgia, 59, 205 (1960); P. Duncumb. Brit. J. Appl. Phys., 10, 420 (1959); 11, 169 Card 3/5





8/048/63/027/003/020/025 B106/B238

AUTHORS:

Kushnir, Yu. M., Setisov, D. V., Raspletin, K. K., Pochtarev, B. I., Spektor, F. U., Gurova, R. P., Tokarev, I. D., Osipov, V. N., and Pavlov, V. A.

TITLE:

A modified raster microscope - local X-ray microanalyzer

and its use

PERIODICAL: Akademiya nauk SSSR. Izvestiya. Seriya fizicheskaya, v. 27

no. 3, 1963, 415-419

TEXT: A modified scanning electron microscope - local X-ray microanelyzer is described briefly, and a few data are on its use in investigating metals, minerals and semiconductors presented. The crystal X-ray spectrometer of the apparatus makes it possible to analyze the radiation of elements from magnesium to uranium. The dead time of the counter tube does not permit of obtaining qualitative X-ray patterns when the scanning velocities are high. The authors therefore developed a system of slow scanning which provides a scanning field with a 1: 1 format and a resolution of 200 - 300 lines at 1 frame/min. The area of the scanning Card 1/3

S/048/63/027/003/020/025 B106/B238

A modified raster microscope - local ... field on the object amounts to 0.04 to 0.25 mm2. Under these conditions, the dead time of the counter tube imposes practically no limit on the resolution of the characteristic X-rays patterns. A block of slow sweeps serves for observing the images visually, and is provided with a moving film camera with a large afterglow. A second moving film camera, synchronized with the first, records the images photographically; it focuses the spot sharply and has a high accelerating voltage. The characteristic X-ray pattern were also recorded using an NaI-crystal scintillation counter which worked satisfactorily at wavelengths below 1.5 A. The sharpness and contrast of the images obtained due to the secondary electrons were increased by a special device for correcting the frequency characteristics of the video amplifier block. This was done by filtering out signals between 25 and 150 cps and those near to 5 Mcs. The improvements of the basic elements of the X-ray microanalyzer made it possible to obtain characteristic X-rays patterns for the first time, and to undertake comparitive studies of a few objects on the basis of the microphotographs. Besides making it possible to obtain reflected characteristic electron beam and X-ray patterns for macroscopic surfaces, the instrument also permits the vizualization of p - n transitions in Card 2/3

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A modified raster microscope - local ... B106/B238

semiconductors. The band width of the barrier layer depends on the applied voltage and can easily be determined. The authors are now working to develop a raster microscope - local X-ray analyzer as an industrial model; this will feature magnetic optice, thus making it possible to achieve high resolution and a much higher current density in the electron probe. There are 5 figures.

Cerd 3/3

KUSHNIR, Yu.M.; FETISOV, D.V.; DER-SHVARTS, G.V.; POCHTAREV, B.I.; TOKAREV, P.D.;
RASPLETIN, K.K.; SPEKTOR, F.U.; GUROVA, R.P.; POSTNIKOV, Ye.B.;
OSIPOV, V.N.; PAVLOV, V.A.; POGUDINA, M.V.

Combined scanning electron microscope and X-ray microanalyzer with
magnetic electron optics. Izv. AN SSSR. Ser. fiz. 27 no.9:
1166-1172 S '63. (MIRA 16:9)

(Electron microscope) (X-ray spectroscopy)

KUSHNIR, Yu.M.; FETISOV. D.V.; DER-SHVARTS, G.V.; POCHTAREV, B.I.; TOKAREV, P.D.;
RASPLETIN, K.K.; GUROVA, R.P.; POSTNIKOV, Ye.B.

The REMP-1 scanning-type electronic microprobe instrument. Zav.lab. 30
no.12:1510-1512 '64. (MIRA 18:1)

SOURCE: Pribory i tekhnika eksperimenta, no. 1, 1965, 189-191

TOPIC TAGS: microanalyzer, structural analysis

ABSTRACT: An x-ray microanalyzer (MA) intended for structural analyses of reas of thin (2000 Å) folis is described. The MA is built into a desk-type structuran microscope ("Tesla," Czechoslovakia) whose resolution is up to the process of th

ACCESSION NR: AP5007055

ASSOCIATION: none
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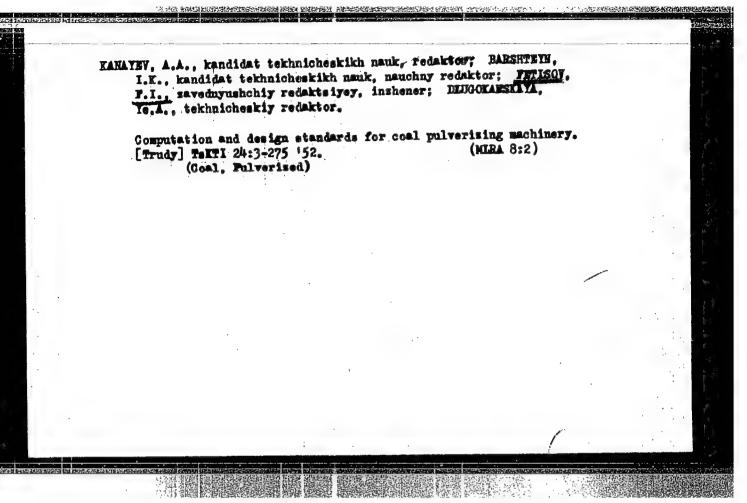
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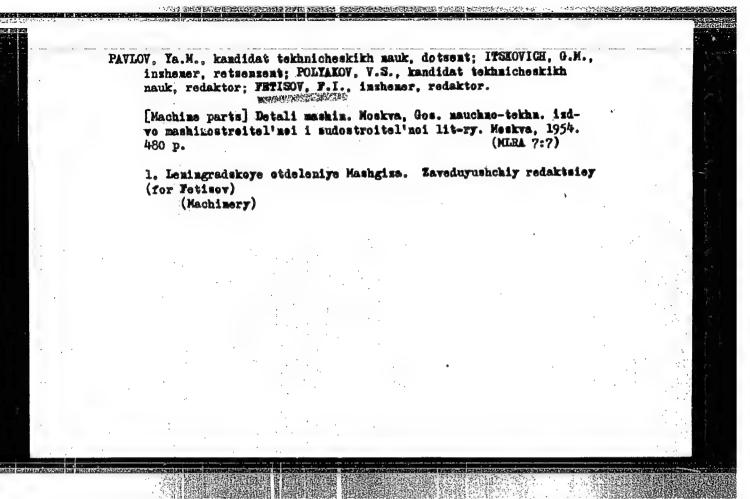
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MANDEL'SHTAM, S.L.; VASIL'IEV, B.N.; VONON'KO, Yu.K.; TINDO, I.P.;
SHURYGIN, A.I.; FETISOV, E.N.

"Of the short-wavelength end of the sun spectrum by means of satellites and rockets."

Report presented at the Spectrascopicum, 11th Intl. Caihoq, Belgrade, Yug, 30 Sep - 4 Oct 63.





FETISOV, G. G.

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FETISOV, G. G. Osnovopolozhnik agrobiologicheskoy nauki. (K 14-Y Godovshchine so diya smerti I. V. Michurina). Sov. zootekhniya, 1949, 110. 3, S. 3-9.

SO: Letopis, No. 32, 1949.

od survey textbook ("I	Fruit and berry s. Reviewed by	orchard in to. G. G. Fetiso	the central zon	e of the U.S. glia, No. 1,	1952.	
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SO: Monthly List	. B. Dunadan Assas	antona Idhwa	of Congress	June	2 195 4 .	Uncl.

FETISOV, G. G.

G. G. Fetisov, Plodovodstvo i yagodovodstvo Fruit and Berry Growing, ninth edition,

Sel'khozgiz, 29 sheets - 1953.

The previous edition has undergone the following revisions and addutuibs; recent data on advanced experience; enlarged description of the varieties of faults and berries. The latest requirements for standardization, regional demarcation, pest control, etc are also included.

The book is intended for the pupils of agricultural middle schools to train kolkhos

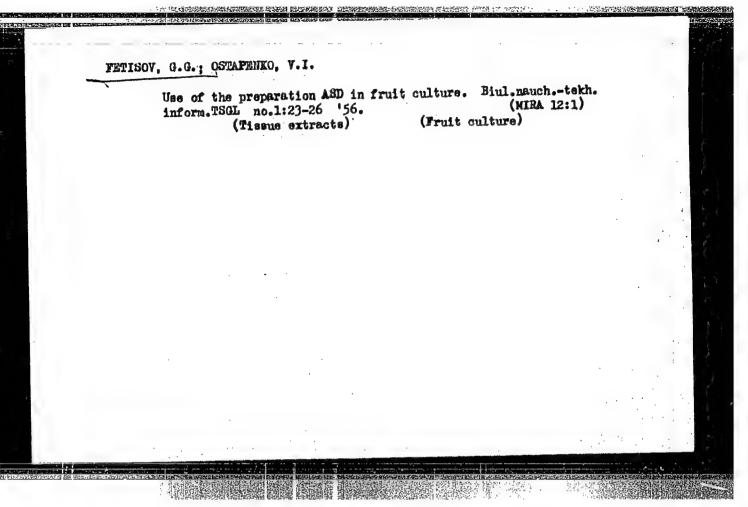
leadership cadres. It may be useful to the practical orchardist.

SO: U-6472, 12 Nov 1954

TARASENKO, Mikhail Trofimovich; YMTISOV, Q.Q., redaktor; TAIROVA, V.H.,
redaktor; PERESTPKINA, Z.D., tekhnicheskiy redaktor; ZUERILINA, Z.P.,
tekhnicheskiy redaktor

[Rejuvenation of a variety] Obnovlenie sorta. Moskva, Gos. izd-vo
selkhoz. lit-ry, 1956, 206 p. (MIRA 9:11)

(Fruit oulture)



KAMSHILOV, N.A.; ANTOHOV, M.V.; BAKHAREV, A.N.; BLINOV, L.F.; BORISOGLEBSKIY,

A.D.; GAR, K.A.; GARIMA, K.P.; GORSHIN, P.F.; GUTITEV, G.T.;

DELITSINA, A.V.; DURROVA, P.F.; YEVFUNENEMO, A.F.; YEGOROV, V.I.;

YERMENKO, L.L.; YEFINOV, V.A.; ZHILITSKIY, Y.A.Z.; ZHUCHKOV, N.G.,

prof.; ZAYETS, V.K.; ISKOL'DSKAYA, R.B.; KOLESHIKOV, V.A., DROF.;

KOLESHIKOV, Y.E.V.; KOSTIMA, K.F.; KRUGLUVA, V.A.; LEONT'YEVA, M.N.;

LESYUK, YE.A.; MUKHIN, YE.N.; HAZARYAN, Y.A.; HEGRUL, A.M., prof.;

ODITSOV, V.A.; OSTAPENKO, V.I.; PERRUSEVICH, P.S.; PROSTOSERDOV,

N.N., prof.; RUKAVISHNIKOV, B.I.; PYRADOV, I.N.; SABUROVA, V.V.;

SABUROVA, T.N.; SAVZDARO, V.E.; SEMIN, V.S.; SIMOHOVA, M.N.;

SMOLYANIMOVA, N.K.; SOBOLEVA, V.F.; TARASKANO, M.T.; PETISOY, G.G.;

CHIZHOV, S.T.; CHUGUNIN, Y.A.V., prof.; YAZVITSKIY, M.N.;

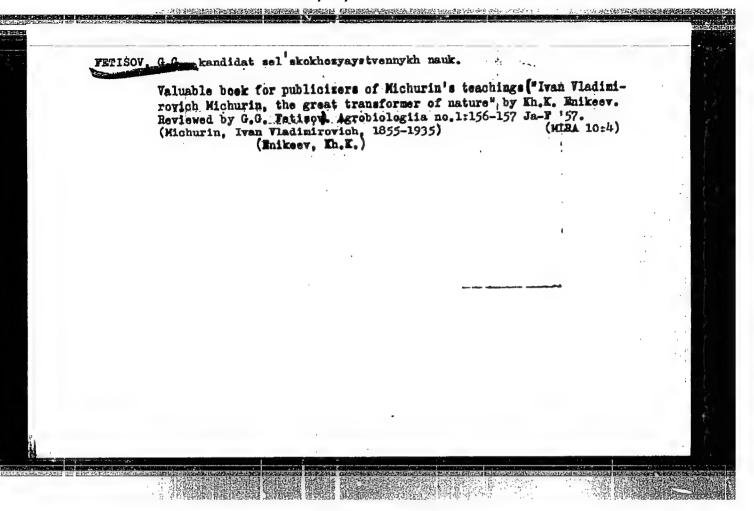
ROSSOSHCYANSKAYA, V.A., red.; BALLOD, A.I., tekhn.red.

[Fruitgrower's dictionary and handbook] Slover'-spravochnik

sadovoda. Moskva, Gos,izd-vo sel'khoz.lit-ry, 1957. 639 p.

(MIRA 11:1)

(Fruit culture—Dictionaries)



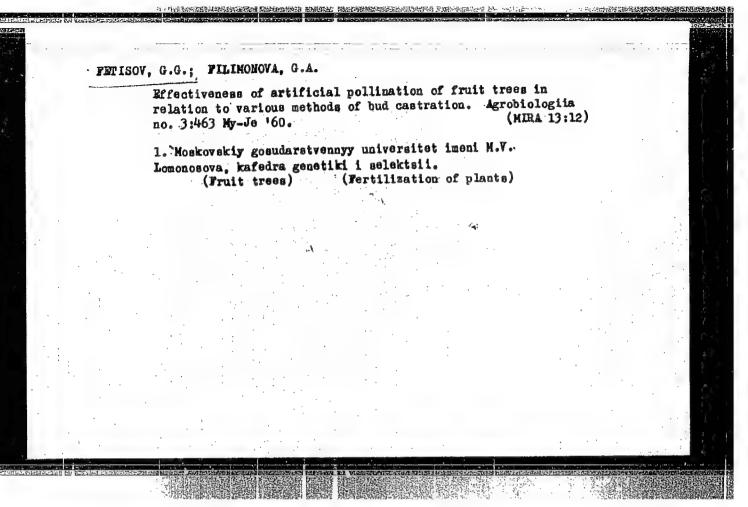
FETISOV, G.G.; KRYUKOVA, N.S.

Changes in the physiological properties of pollen in some apple varieties. Nauch. dokl. vys. shkoly; biol. nauki no.1:120-122 160.

(MIRA 13:2)

1.Rekomendovana Botanichenkim sadom Moskovskogo gosudarstvennogo universiteta im. M.V. Lomonosova.

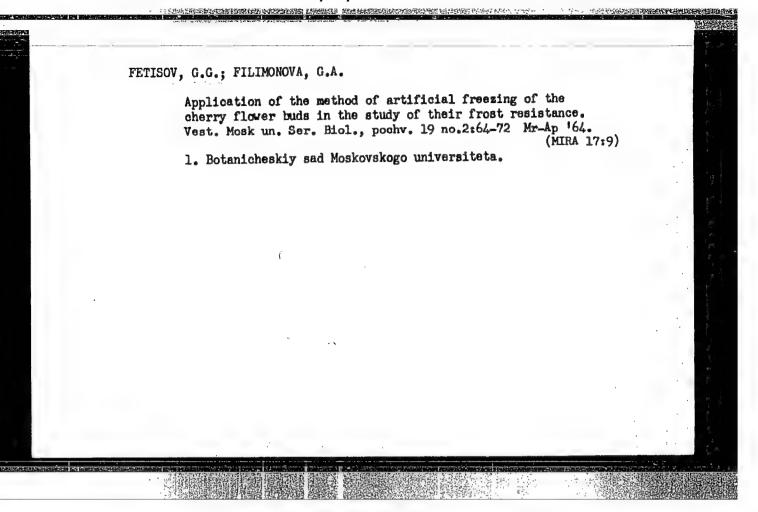
(Apple) (Pollen)



FETISOV, G.G.; FILIMONOVA, G.A.

Nature and the degree of lower bud damages by low temperatures in stone fruits. Agrobiologiia no.3:377-382 My-Je '62* (MIRA 15:10)

1. Moskovskty gosudarstvennyy universitet imeni Lomonosova, kafedra genetiki i selektsii. (STONE FRUIT) (PLANTS—FROST RESISTNANCE)



24(3) AUTHOR:

Fetisov, I. K.

sov/56-36-4-23/70

TITLE:

A Wall Probe in a Magnetic Field (Stenochnyy zond

v magnitnom pole)

PERIODICAL:

Zhurnal eksperimental noy i teoreticheskoy fiziki, 1959,

Vol 36, Nr 4, pp 1110-1118 (USSR)

ABSTRACT:

Spivak and Reykhrudel' (Ref 1) gave a generalization of the Langmuir theory of probe measurements in the case of weak magnetic fields (~10 0e). In the present paper the author investigates current measurements by means of a wall probe in strong (~1000 0e) magnetic fields. The paper consists of two parts. In the first, probe measurements in a compensated ion beam are dealt with, and the second deals with probe measurements in the plasma of a gas discharge. Calculations are based on the following assumptions: Between two conductive planes a quasineutral plasma is assumed to be located, which is formed by the ionization of the residual gas by fast ions. The H-direction is assumed to be vertical to the conductive planes (= z-direction). The ion

Card 1/4

sov/56-36-4-23/70

A Wall Probe in a Magnetic Field

current density is assumed to be constant with respect to z. Vertically to H, the plasma is assumed to be unlimited. The disk-shaped probe is assumed to be in one of the planes (i. e. vertical to H) (Fig 1). By basing upon these geometrically given conditions, a formula for the current J on to the probe is first derived. Calculations are followed step by step.

The final formula is $J - J_0 = -2\pi nDl \frac{x_0}{T} \frac{dy}{dx} \Big|_{X = x_0}$

(J_{o} is the current on to the probe if the probe potential is zero, n is the electron concentration, which is equal to the concentration of the fast ions, which is equal to the concentration of the fast ions, which is equal to the concentration of the fast ions, which is equal to the concentration of the fast ions, the electron temperature in v, x = kr, $x_{o} = kr_{o}$, the electron temperature in v, x = kr, $x_{o} = kr_{o}$, the probe radius, $k^{2} = j_{z}^{o}/\text{nDl}$, j_{z}^{o} denotes electron current density on the probe). For the case in which the probe potential U_{s} is low, one obtains $J - J_{o} = \pi n \text{ Dlkr}_{o} U_{s}/T$ in the case of great kr_{o} , i. e.

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A Wall Probe in a Magnetic Field

SOV/56-36-4-23/70

in the case of great kr the current to the probe is proportional to the probe radius, and in the case of small kr it is proportional to the square of the probe radius. In general it holds that $J - J_0 = 0.4\pi nDlj$. In the second part of the paper conditions are investigated for the limiting case in which the concentration of the slow ions is high compared to that of fast ions. The plasma is assumed to consist of electrons of the temperature T and slow ions of the temperature T_1 , where it is assumed that $T_1 \ll T$. The slow ions are assumed to be formed by ionization of the residual gas by an external source, by fast ions or electrons, or else by the re-charge of ions. In this case the variation of the plasma potential U in the case of variation of the probe potential is limited by a quantity of the smallness of T_+ . V_o may be considered to be invariable. By basing on these assumptions, the electron current to the probe is investigated first for

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A Wall Probe in a Magnetic Field

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the case in which there is no ionization. Rather complicated formulas are derived for $J_- = J_-^0$. Finally, the current of positive ions to the probe is investigated, and a formula is given for $J_+ = J_+^0$. The author in conclusion thanks 0. B. Firsov and A. V. Zharinov for their help and discussions. There are 2 figures and 3 references, 2 of which are Soviet.

SUBMITTED:

September 5, 1958

Card 4/4

24 (5), 24 (7) 807/56-37-1-14/64 Fetisov, I. K., Firsov, O. B. AUTHORS: The Resonance Charge Exchange of Doubly Charged Ions in Slow TITLE: Collisions (Rezonansnaya perezaryadka dvukhzaryadnykh ionov pri medlennykh stolknoveniyakh) Zhurnal eksperimental'noy i teoreticheskoy fiziki, 1959, Vol 37, PERIODICAL: Nr 1(7), pp 95 - 97 (USSR) The authors of the present paper calculate the cross-section of ABSTRACT: the resonance charge exchange of doubly charged ions in adiabatic approximation, and then they compare the experimental and theoretical cross sections of the charge exchange of doubly charged positive ions of A, Kr, Xe, Ne. This problem is reduced to the calculation of the separation of the electron levels in the approximation of nuclei. The authors presuppose that with not very small distances between the atomic nuclei, the difference E - E can be calculated by substituting $\psi_{c,a} \sim [\varphi_A(r_1,r_2) \pm \varphi_B(s_1,s_2)] / \sqrt{2}$ for He⁺⁺. E_a and E_c denote the energy level of electrons corresponding to the antisymmetric and symmetric wave functions, respectively. ϕ_{A} and ϕ_{B} denote the Card 1/3

The Resonance Charge Exchange of Doubly Charged Ions 50V/56-37-1-14/64 in Slow Collisions

wave functions, belonging to helium, of electrons in the ground state if the electrons belong to nucleus A and B, respectively. Formulas for the energy of the electrons are given in first approximation. Most simple helium functions of the type G $C \exp \left[-\alpha(x_1+x_2), \alpha = a_0^{-1}\sqrt{(E_1 + E_2)/2E_0}\right]$ were used as functions φ . $E_1 + E_2$ denote the total energy of the electrons of the atom, E the energy of the electron in the hydrogen atom, a the Bohr radius. The theory discussed in the present paper is suitable for the relative velocities defined by the inequality v & (ae2/h)a. The results of calculations are illustrated in a diagram. The relative velocity of motion of the nuclei is plotted on the axis of abscissas, $\alpha^2\sigma$ on the axis of ordinates, σ denoting the cross section of the charge exchange of two electrons. The curve contained in this diagram falls almost linearly downward to the right, only in its initial range it is a little concave upward. The same diagram contains the experimentally measured cross

Card 2/3

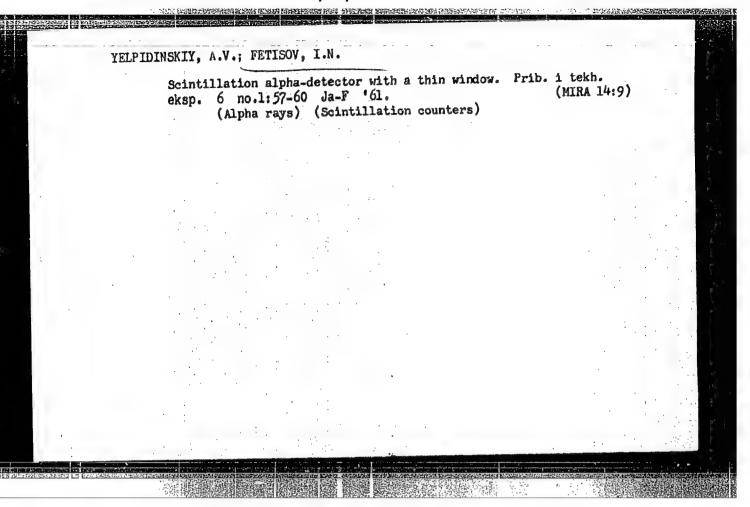
The Resonance Charge Exchange of Doubly Charged Ions in SOV/56-37-1-14/64 Slow Collisions

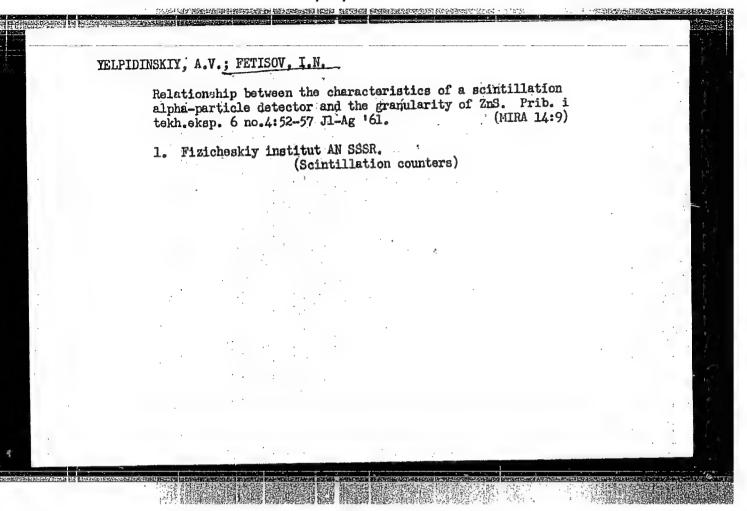
sections of the two-electron charge exchange of the rare gases A, Ne, Kr, Xe. As the one-electron charge exchange proceeds in the same degree by means of the two-electron charge exchange and by means of elastic scattering (which was not considered in the calculation of the cross section), the theoretical curve rather corresponds to the sum σ_{20} + $(1/2)\sigma_{21}$, σ_{20} denoting the cross section of the two-electron charge exchange, and σ_{21} the cross section of the one-electron charge exchange. In the second diagram, the experimental results for the case just mentioned are compared with theory. In the authors' opinion, the results found here agree better with the experiment than those found by Gurnee and Magee (Ref 9). There are 2 figures and 11 references, 3 of which are Soviet.

SUBMITTED:

December 29, 1958.

Card 3/3





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s/089/62/013/002/003/011 B102/B104

AUTHORS:

Yelpidinskiy, A. V., Fetisov, I. N.

TITLE:

The photoneutron yield and shielding problems of high-energy cyclic electron accelerators

PERIODICAL:

Atomnaya energiya, v. 13, no. 2, 1962, 140-144

TEXT: The giant-resonance photoneutron yield of various metals in absorptions of electrons with more than 30 MeV was calculated. The yield Q is obtained from the photon equilibrium spectrum $\bigcap_{ph}(E,E_o)$ of primary electrons with E_o from the relation

Q = Nnt_o $\int_{E}^{E_o} \sigma_{ph}(E) \Gamma_{ph}(E, E_o) dE$

where N is the number of absorbed electrons, n the number of nuclei per cm² of the absorber, t_0 the radiation length, E_n the (γ,n) threshold energy, $\sigma_{\rm ph}$ the total photoneutron production cross section. An approximation, Card 1/3

S/089/62/013/002/003/011 B102/B104

The photoneutron yield and ..

sufficient for calculating the shielding, gives Q = $1.5 \cdot 10^{-4}$ NE sec⁻¹ for an averaged neutron yield. This relation holds for any E₀ $\gg 30$ Mev (E₀ is the electron energy at the end of the acceleration cycle in Mev and N is the number of electrons accelerated during one second. In most cases all neutrons can be assumed to have formed either in the acceleration material or in the shield. If, furthermore, the dimensions of the apparatus are or in the shield. If, furthermore, the dimensions of the apparatus are so chosen that the accelerator can be regarded as a point source, then so chosen that the accelerator can be regarded for the smallest a value of h = $36 \log(NE_0/R^2)$ - 340 [cm] is obtained for the smallest

necessary shield thickness if the shield consists of ordinary concrete, R being the distance [m] of the external shield wall from the accelerator. This thickness guarantees a neutron flux weakening to 3 n/cm² sec. The corrections for the finite dimensions of the accelerator can be made by corrections for the finite dimensions of the accelerator can be made by the usual formulas. These estimates of shield thickness take no account of the neutrons due to bremsstrahlung. This kind of neutron radiation, however, depends considerably on the shield structure. It constitutes a local hazard greater than primary bremsstrahlung only when the concrete shield contains additional layers heavy metal (>15 cm Pb or 35 cm Fe).

Card 2/3

S/089/62/013/002/003/011

The photoneutron yield and ... B102/B104

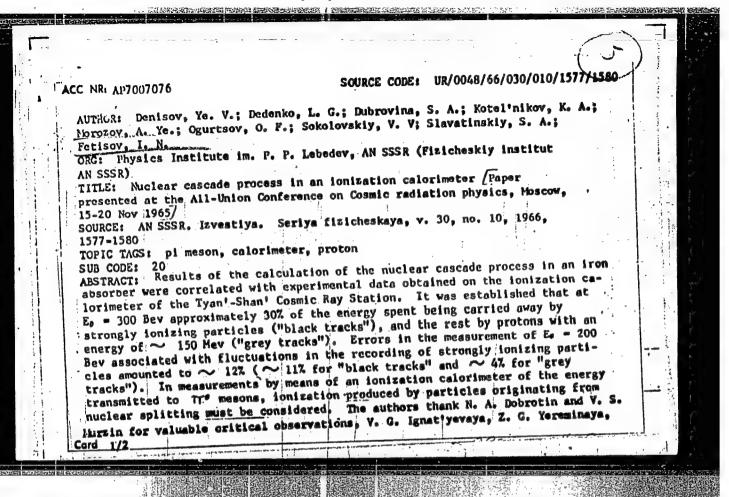
In this case η ≤1, otherwise η ≃2·10⁻³ (η is the ratio between neutron radiation hazard and primary bremsstrahlung hazard). There is 1 table.

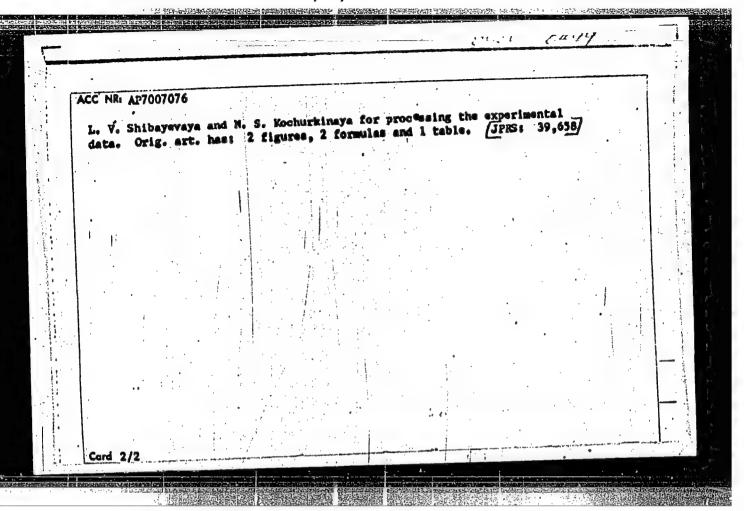
SUBMITTED: June 29, 1961

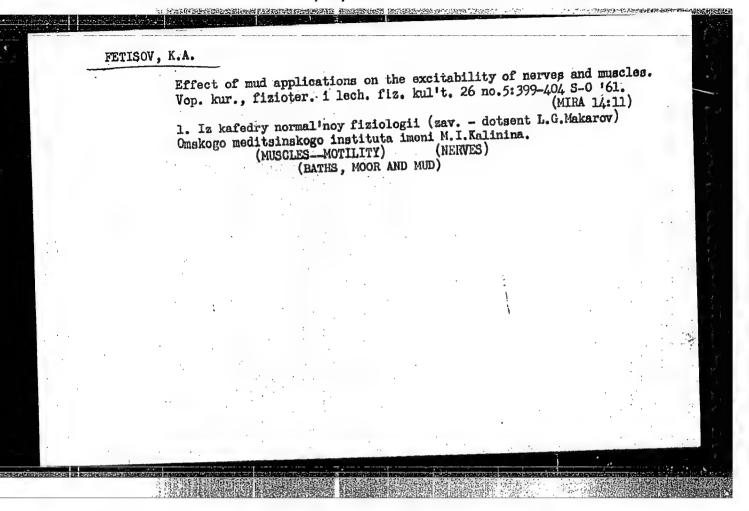
SLAVATINSKIY, S.A.; FETISOV, I.N.

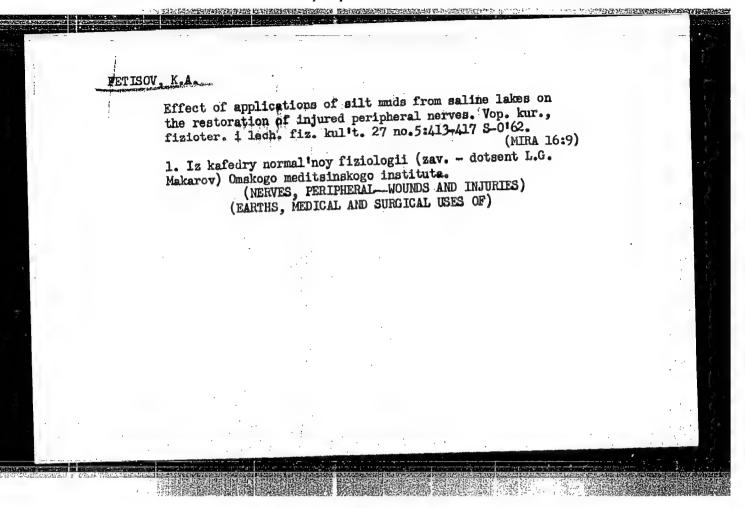
Cross sections of the generation of K^O-mesons and hyperons at energies of hundreds of Bev. Izv. AN SSSR. Ser. fiz. 28 no.ll:1758-1760 N '64. (MIRA 17:12)

1. Fizicheskiy institut im. P.N. Lebedeva AN SSSR.







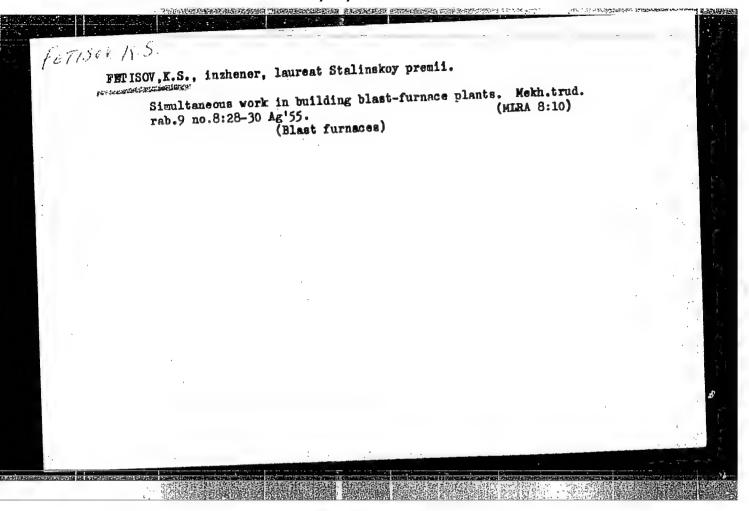


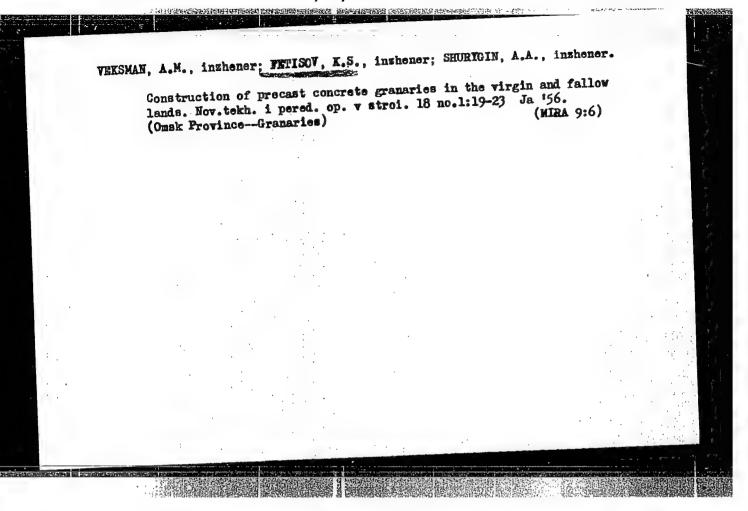
Fetisov, K. K.

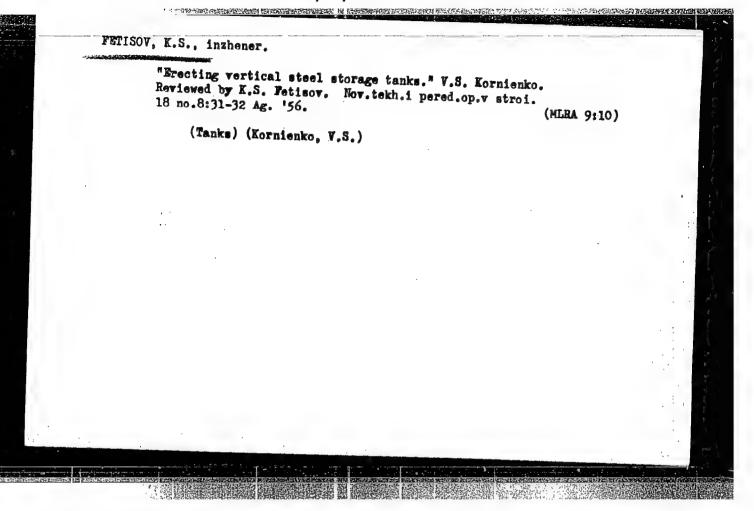
Fetisov, K. K.

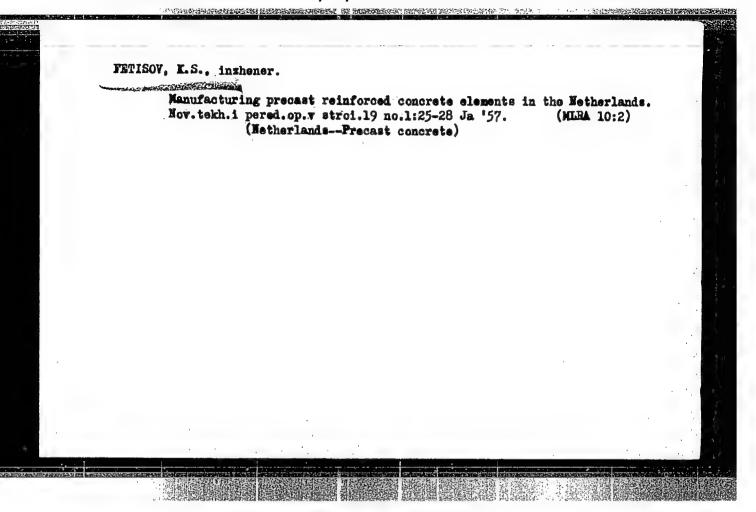
"A study of spring wheat from the high mountanious regions of Georgia under the conditions of the northern European portion of the RSFS." All-Union Order of Lenin Academy of Agricultural Sciences imeni V. I. Lenin. All-Union Inst of Plant Growing. Moscow, 1956 (Dissertation for the degree of Candidate in Agricultural Sciences)

Knizhnaya letopis
No. 15, 1956. Moscow



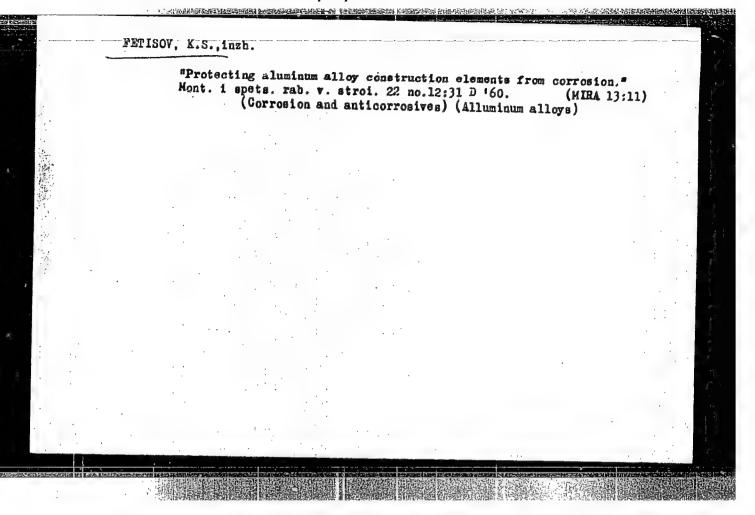






Using aluminum alloys in construction. Mont.i spets.rab.v stroi.
22 no.10:1-6 0 '60. (MIRA 13:9)

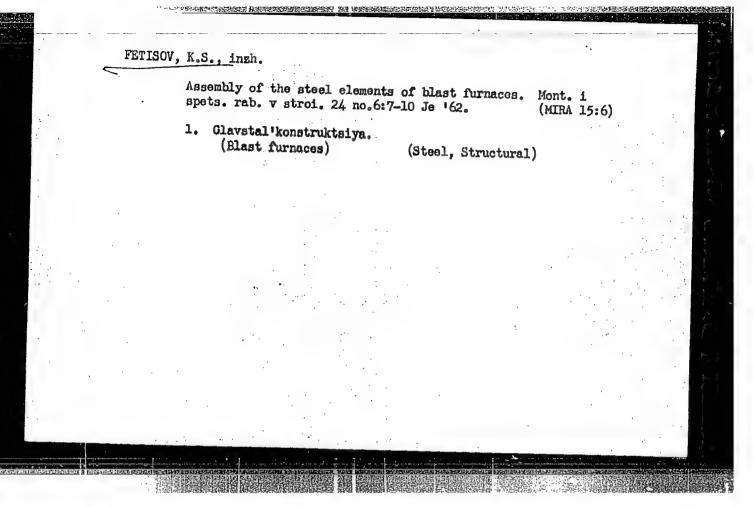
1. Glavstal'konstruktsiya Minstroya RSFSR.
(Aluminum alloys) (Factories—Design and construction)

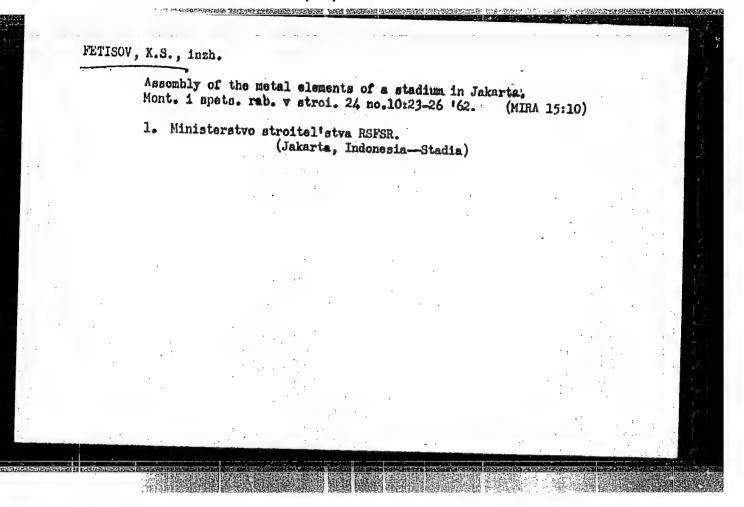


KORNIYENKO, V.S., inzh.; FETISOV, K.S., inzh.

Assembly of blast heaters from rolled blanks. Mont. i spets.
rab. v stroi. 23 no.12:2-4 D *61. (MIRA 15:2)

1. Proyektnyy institut Promstal*konstruktsiya i Glavstal*
konstruktsiya Minstroya RSFSR.
(Blast furnaces—Equipment and supplies)

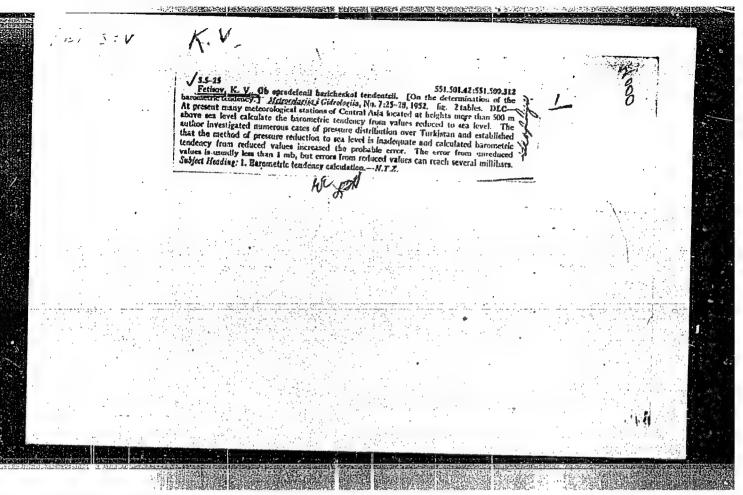


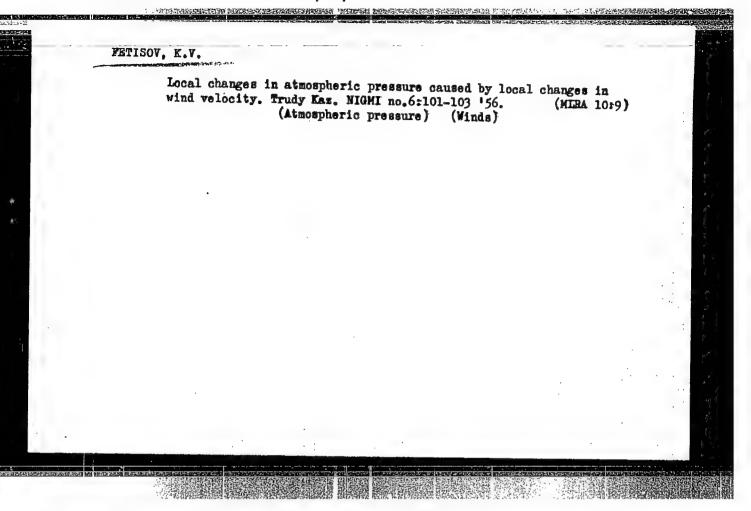


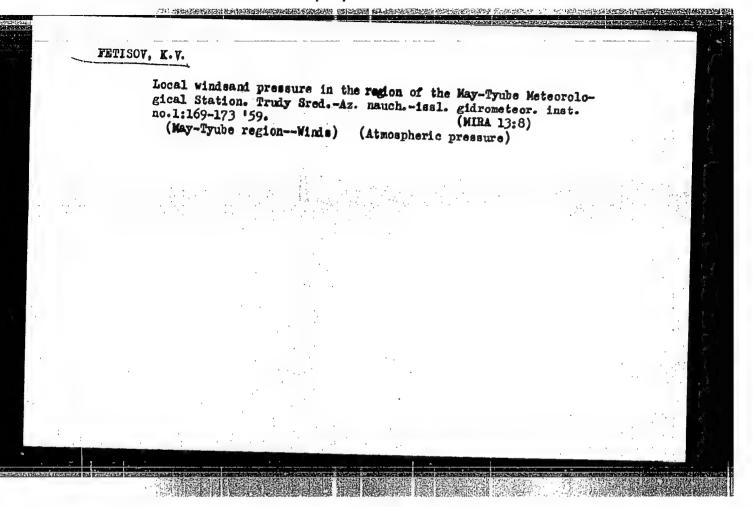
BONDAR', Ye vgeniy Petrovich, inzh.; FETISOV, Konstantin Semenovich, laureat Cosudarstvennoy premii, inzh.; KALININ, B.P., inzh., nauchn. red.; YUDINA, L.A., red.; SHERSTNEVA, N.V., tekhn. red.

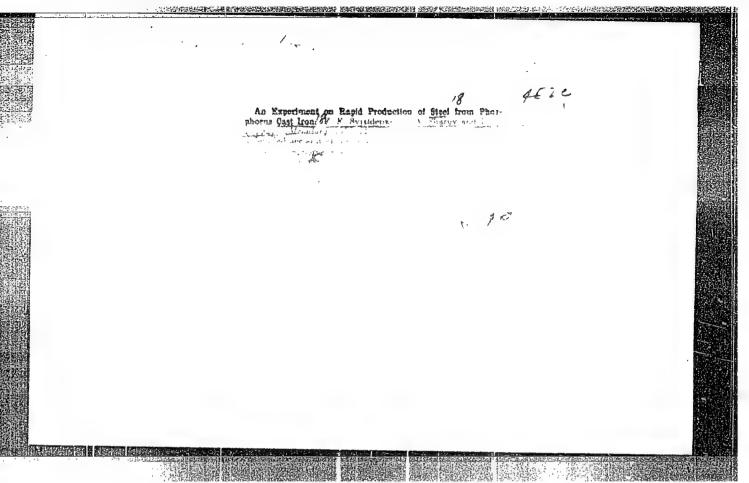
[Assembling reinforced concrete structures] Montazh zhelezobetonnykh konstruktsil. Moskva, Gosstroilzdat, 1963, 246 p.

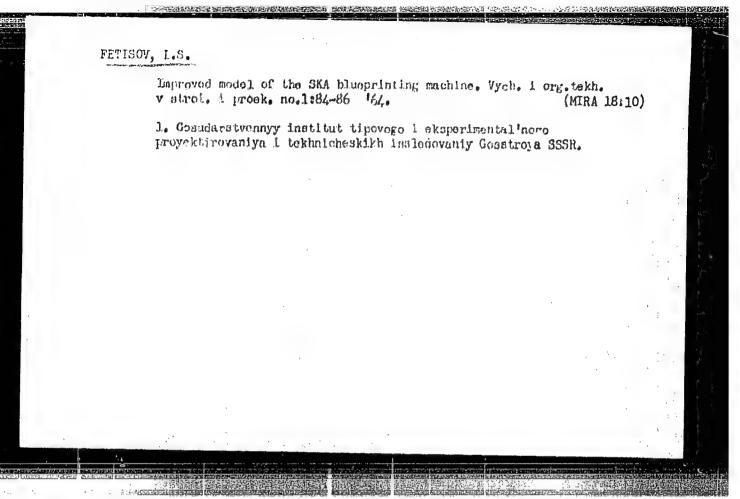
(MIRA 17:1)

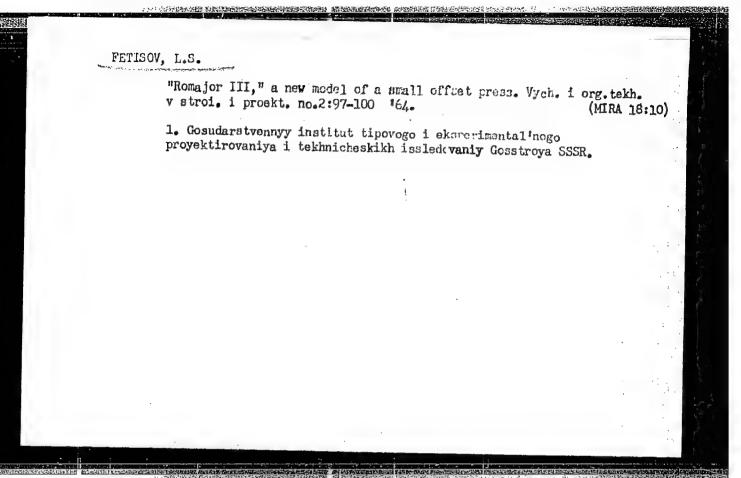












FETISOV, L.S.

Recommendations for remodeling the "Stankin" (SKA-1) and the "Viskhom" (SKM-4) blueprinting machines. Vych. i org.tekh. v stroi. i proekt. no.3:78-80 %4. (MIRA 18:10)

1. Gosudarstvennyy institut tipovogo i eksperimental'nogo proyektirovaniya i tekhnicheskikh issledovaniy Gosstroya SSSR.

Contribution of scientists to agricultural workers. Okhr. truda i sots. strakh. 6 no.12:10-13 1 163. (MIRA 17:2)

1. Direktor Saratovskogo mauchno-issledovatel'skogo instituta

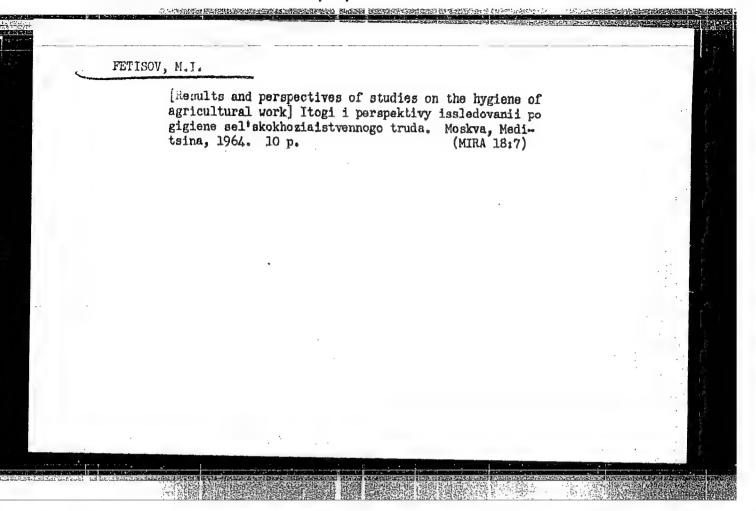
FETISOU, MAKHAIL LUANGUICH

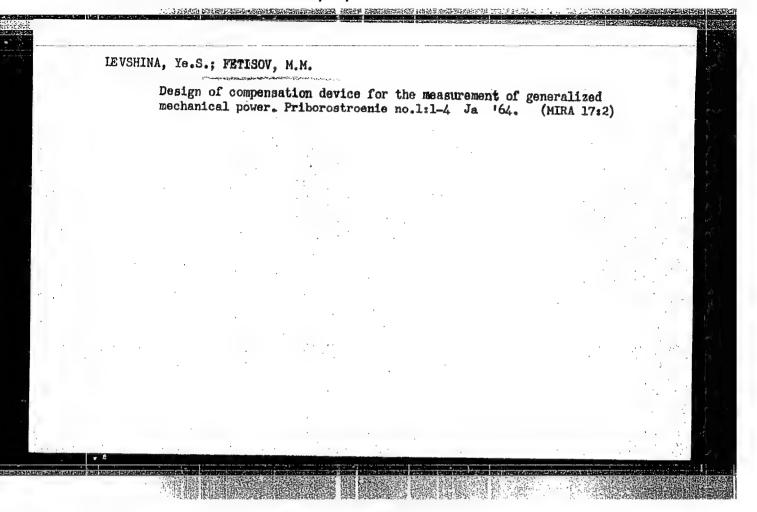
FETISOV, Makhail Ivanovich

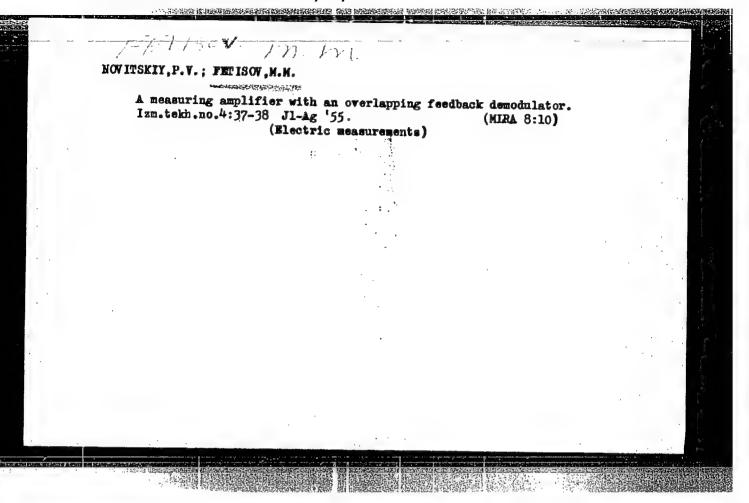
FETISOV, Makhail Ivanovich - Academic degree of Doctor of Philological Sciences, based on his defense, 28 October 1955, in the Council of the Inst of World Literature inemi Gor'kiy Acad Sci USSR, of his dissertation entitled: "Literary ties of Russia with Kazakhstan (Thirties-Fifties of the Nineteenth Century)."

For the Academic Degree of Doctor of Sciences

SO: Byulleten' Ministerstva Vyshego Obrazovaniya SSSR, List No. 2, 21 January 1956, Decisions of the Higher Certification Commission concerning academic degrees and titles.







Translation from: Referativnyy zhurnal, Mekhanika, 1957, Nr 5, p 117 (USSR) SOV/124-57-5-5846

AUTHOR: Fetisov, M. M.

TITLE:

Using Induction-type Pressure Transducers to Measure Transient Pressures (Ispol'zovaniye induktivnykh preobrazovateley dlya izmereniya nestatsionarnykh davleniy)

PERIODICAL: Tr. Leningr. politekhn. in-ta, 1955, Nr 176, pp 214-227

ABSTRACT: The author examines the various methods used in the calculation and design of induction-type pressure transducers. He lists those conditions fulfillment of which will, in his opinion, result in the maximum possible relative sensitivity of one of the most important of the transducer parameters. He indicates those transducer circuit connections which he deems most suitable for finite-resistance loads and for infinite-resistance loads (i. e., for the input of an electron-tube amplifier). Included are design specifications for transducers (with and without amplifiers) intended for measuring variable pressures. A description and schematic diagram are given of the design of one model of a small-size induction-type differential (hybrid-coil) trans-Card 1/2 ducer (for use with amplifier). This transducer, having an over-all

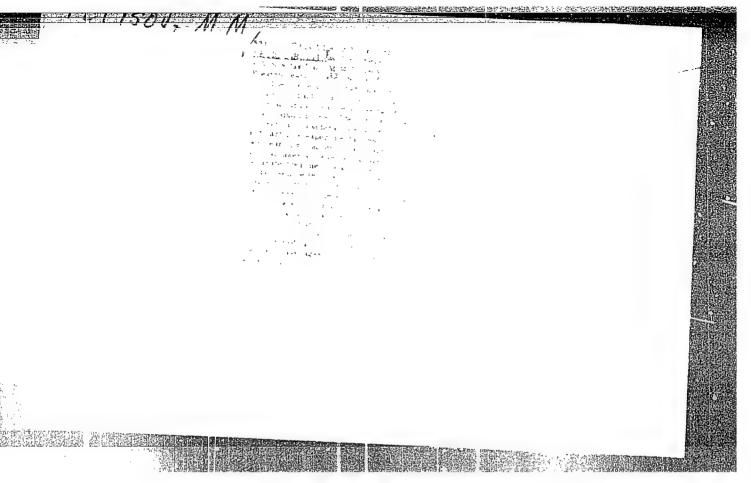
SOV/124-57-5-5846

Using Induction-type Pressure Transducers to Measure Transient Pressures

size of 11 x 9 mm, is capable of measuring extremely low pressures. For example, with a transducer-membrane thickness of 0.03 mm and a starting gap of 0.1 mm, the type-VIII vibrator of an MPO-2 oscilloscope exhibits a full beam deflection at a pressure of only 1.5 mm H2O. Within a broad range of pressures the calibration curve is linear, and the transducer's operating voltage on an 800cps power-source current frequency is 12 volts in both coils. Included is a circuit diagram for a pressure-measuring apparatus intended for use with an inductiontype transducer without an amplifier; design specifications for a transducer of this type are given also. Depending on the thickness of its membrane, a transducer of this type will measure effectively gas and liquid pressures over the very broad pressure range from 15 mm to 10 m H2O. For all practical purposes the transducer is quite sufficiently sensitive and its calibration curve may be regarded as linear. In conclusion, the author cites several possible design features that would balance out the effect of a relatively large constant-pressure component of gas and liquid total pressures exhibiting only very small variations. Bibliography: 7 references.

N. A. Preobrazhenskiy

Card 2/2



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SOV/112-59-4-7314

Translation from: Referativnyy zhurnal. Elektrotekhnika, 1959, Nr 4, p 123 (USSR)

AUTHOR: Fetisov, M. M.

TITLE: Some Problems in the Theory of Automatic Instruments With Compensation of the Nonelectric Quantity Being Measured (Instruments With Inverted Transducers)

PERIODICAL: Nauchno-tekhn. inform. byul. Leningrad. politekhn. in-t, 1957, Nr 6, pp 65-80

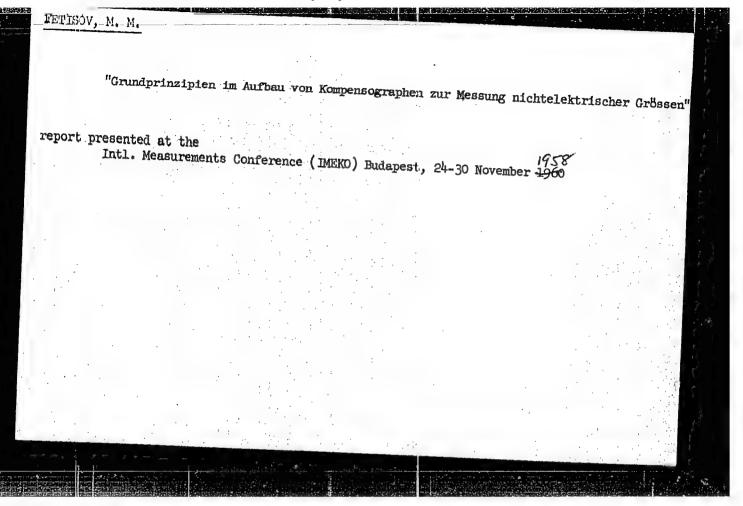
ABSTRACT: The structure of inverted-transducer instruments and its influence on measurement errors are considered. A classification table of inverted transducers with exemplary values of their inherent and temperature errors is suggested. Principal and functional schemes of some Soviet and foreign inverted-transducer instruments are presented. It is noted that with an insufficient stability of the primary transducer (2-4%), the adoption of a compensating-type measurement of nonelectrical quantity with the use of

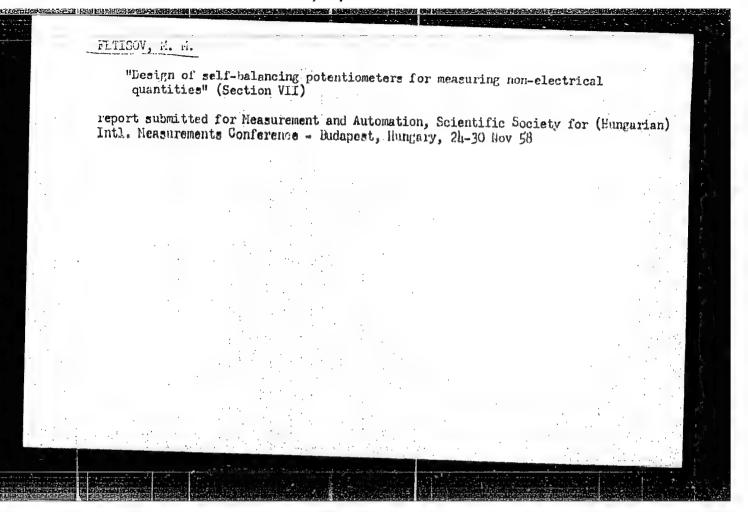
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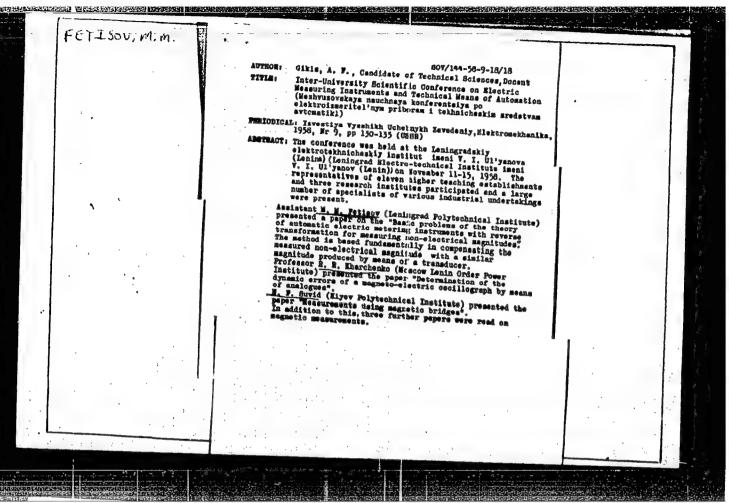
Sow/112-59-4-7314

inverted transducers that have a low error (0.03-0.5%) always brings about a considerable improvement in accuracy. Bibliography: 13 items.

A.F.K.







SOV/146-59-1-7/21 25(1) AUTHOR: Fetisov, M.M., Assistant TITLE: Principles of Building Instruments for Measuring Nonelectric Magnitudes With Compensation of the Nonelectric Magnitude to Be Measured PERIODICAL: Izvestiya vysshikh uchebnykh zavedeniy, Priborostroyeniye, 1959, Nr 1, pp 47-54 (USSR) ABSTRACT: The author reviews the development of electrical instruments for measuring nonelectric magnitudes. He explains briefly the application of inverters for compensation of nonelectric magnitudes to be measured, but does not describe any specific instruments. He describes in more detail an accelerometer for which he received Author's Certificate Nr 113183, dated December 13, 1955, and an instrument for measuring vibration, Author's Certificate Nr 114054, dated June 20, 1957. Finally, he mentions that electrical instruments with compensation of the nonelectric magnitude to be measured were introduced in 1950, but today they Card 1/2 already belong to the class of precision measuring instruments

Principles of Building Instruments for Measuring Nonelectric Magnitudes With

Compensation of the Nonelectric Magnitude to Be Measured

There are 5 block diagrams, 2 circuit diagrams, 2 graphs and 3

ASSOCIATION:

Leuingradskiy politekhnicheskiy institut imeni M.I. Kalinina (Leningrad Polytechnic Institute imeni M.I. Kalinin)

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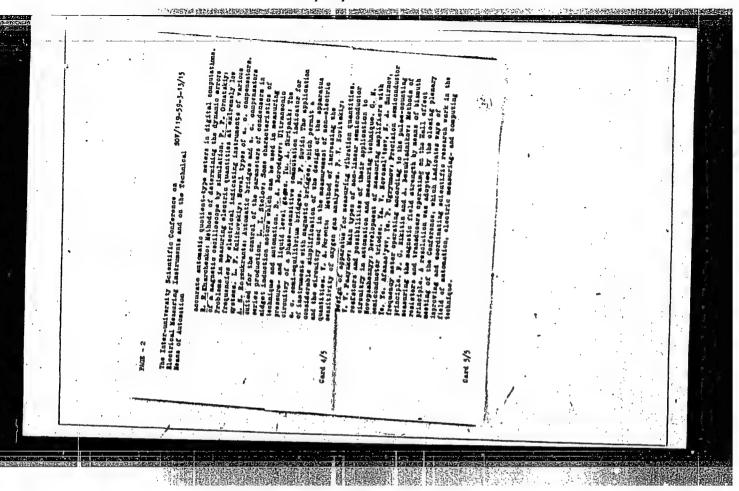
February 14, 1959

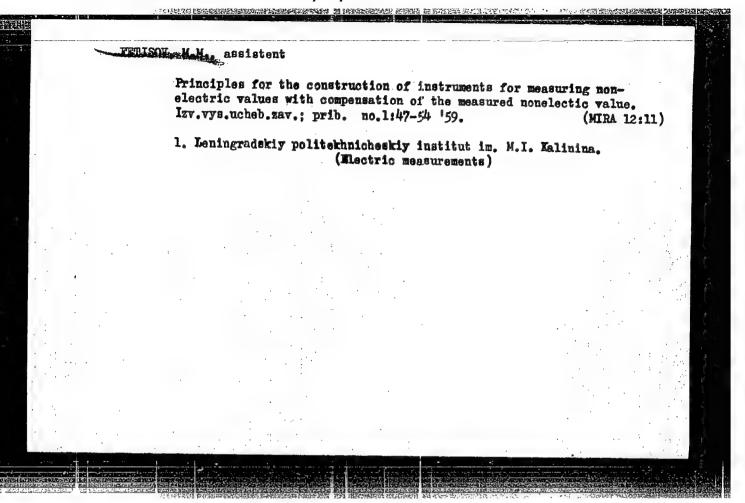
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9(6) AUTHORS: Novitskiy, P. V., Candidate of SOV/119-6 Technical Sciences, Presnyakov, P. D., Engineer, SOV/119-60-1-6/14 Fetisov, M. M., Engineer TITLE: The Construction of Piezoelectric Accelerometers With Minimum Lateral Sensitivity PERIODICAL: Priborostroyenije, 1960, Nr 1, pp 15 - 17 (USSR) A piezoelectric transducer (Fig 1) is theoretically not ABSTRACT: sensitive to oscillations perpendicular to a symmetry axis, i. e. for oscillations in the direction a (Fig 1) it gives no signals. A lateral sensitivity, however, exists due to several causes. As such causes the following are mentioned: Wrong mounting of the accelerometers to the surface of the workpiece, wrong fitting of the piezoelement into the accelerometer, or deformation of the piezoelectric element by the mass 1 (Fig 1). A decrease of the lateral sensitivity of the accelerometer, which is caused by the aforementioned deformation, by fixing the mass 1, was found to be impossible. Card 1/3 It was found useful to introduce the piezoelectric element

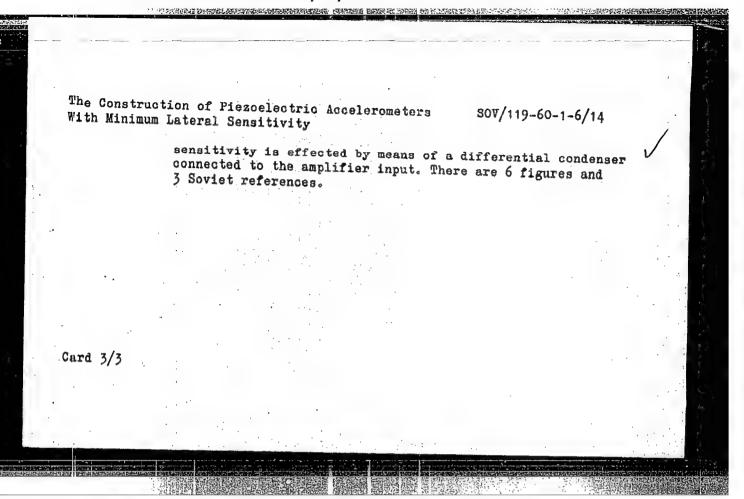
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The Construction of Piezoelectric Accelerometers With Minimum Lateral Sensitivity

SOV/119-60-1-6/14

into the mass 1 according to figure 2a or by the method shown in 2b. As a further means of reducing lateral sensitivity, the authors mention the use of a double-transducer (Fig 3), in which the lateral sensitivity of the two transducers is compensated. A detailed description is given of the transducer developed by E. I. Radion together with the author, which is shown in section in figure 4. This construction makes it possible to adjust the accelerator, so that lateral sensitivity is reduced to a minimum. On the basis of this accelerometer a three-component accelerometer was developed, which does not exhibit the unfavorable properties of similar constructions, as e. g. great weight and unfavorable resonance properties. This accelerometer is shown in figure 6. In this construction the two crystals which are intended to measure lateral acceleration in each case consist of two crystals and are connected in such a manner that the e.m.f. generated by them is mutually compensated. Complete compensation of lateral

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Translation from: Referativnyy zhurnal, Mashinostroyeniye, 1960, No. 24, p. 259 # 133956

AUTHOR:

Fetisov, M.M.

TITLE:

New Compensating Devices of the Seismic Design for Measuring the

Vibration Parameters

PERIODICAL: Nauchno-tekhn. inform. byul. Leningr. politekhn. in-t, 1959, No. 3

pp. 21-32

The theory is considered of compensating accelerometers and vibro-TEXT: meters based on the operation principle of magnetcelectric inverted converter. The movable part of the accelerometer is a coil in a permanent-magnet field; the magnet is fixed to the device housing. The relative displacements of the magnet and coil evoked by acting acceleration are transformed by the displacement transmitter into changes of voltage, which is supplied to the amplifier input; the output current of the amplifier is supplied to the coil and yields the compensating force by its interaction with the magnetic field. The current in the coil is proportional to the acceleration and measured by an ammeter or is supplied to a Card 1/2

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New Compensating Devices of the Seismic Design for Measuring the Vibration Para-

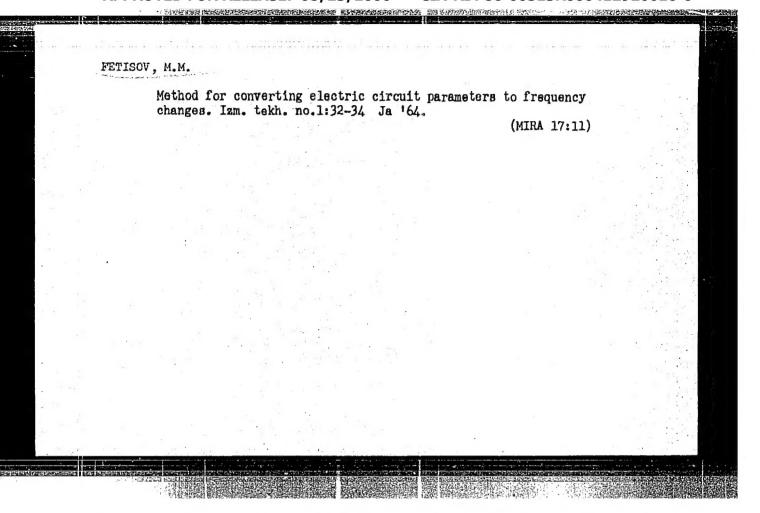
vibrator. The inertial mass of the vibrometer for subsonic frequencies is a magnet in the field of which is a coil fixed to the housing. A secondary inertial mass of the undercompensation converter is suspended on the magnet by means of springs; this converter is used for the conversion of that acceleration into voltage, which acts upon the mass at the device housing vibrations; this voltage is supplied to the amplifier input. The amplifier output current gets into the coil and originates a force, which seeks to keep the magnet with the secondary mass, connected to it, immovable in space. If the amplification factor is sufficiently great, the measured displacement is compensated by the travel of the movable part of the inverted converter; the latter keeps its position in space invariable with high accuracy. The amplitude and the shape of the vibrations are determined by recording the current in the coil. The circuitry, the generalized frequency characteristics of the compensating accelerometer and the vibrometer are presented, and their

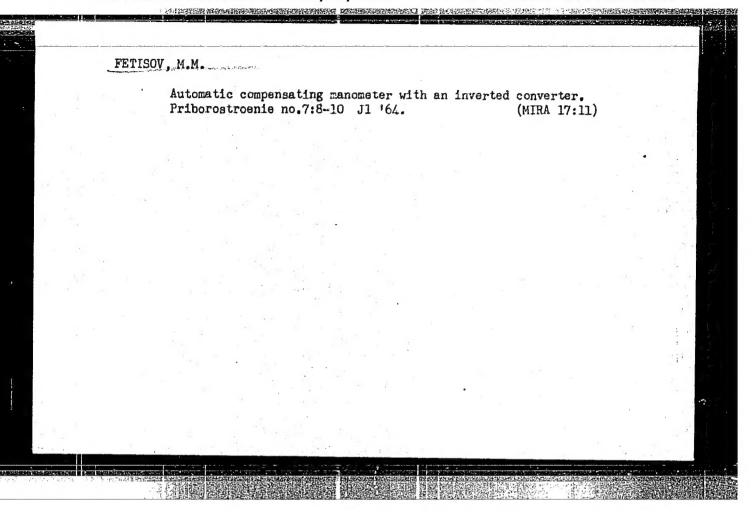
Translator's note: This is the full translation of the original Russian abstract.

SIRAMKOV, Ye.G.; NOVITSKIY, P.V.; FETISOV, M.M.; ZORIN, D.I.

Concerning the structure and some fundamental characteristics of present-day electric measuring devices. Elektrichestvo no.8:20-25 Ag '62. (MIRA 15:7)

1. Leningradskiy politekhnicheskiy institut imeni Kalinina. (Electric measurements)





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AUTHOR: Fetisov, M. M.;	Kremlevskiv. W. P.	\$5 B
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Ille: Errors of Iolione	r-type frequency transducers with square-law circuits	
SCOURCE: Izmeritel'naya t	ekhnika, no. 12, 1965, 35-39	
TYPIC TAGS: frequency ty	pe transducer, electronic circuit, frequency conversion,	error
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